

Tentative

CM100DY-24NF

Pre.	S.Uchida	Rev	B	H. Hanada,
Apr.	M.Tabata 10-Oct.'02			M.Tabata 21-Feb.'03

HIGH POWER SWITCHING USE

Notice : This is not a final specification. Some parametric limits are subject to change.

<p>CM100DY-24NF</p> <p>●I_c.....100A ●V_{CES}.....1200V ●Insulated Type ●2-elements in a pack</p>	
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APPLICATION

General purpose inverters & Servo controls,etc

ABSOLUTE MAXIMUM RATINGS ($T_j = 25\text{ }^\circ\text{C}$)

Symbol	Item	Conditions	Ratings	Units
V_{CES}	Collector-emitter voltage	G-E Short	1200	V
V_{GES}	Gate-emitter voltage	C-E Short	± 20	V
I_c	Collector current	DC, $T_c = 113\text{ }^\circ\text{C}^*3$	100	A
I_{CM}		Pulse (2)	200	
I_E (1)	Emitter current		100	A
I_{EM} (1)		Pulse (2)	200	
P_C (3)	Maximum collector dissipation	$T_c = 25\text{ }^\circ\text{C}$	650	W
T_j	Junction temperature		$-40\sim+150$	$^\circ\text{C}$
T_{stg}	Storage temperature		$-40\sim+125$	$^\circ\text{C}$
Viso	Isolation voltage	Main terminal to base plate, AC 1 min.	2500	V
—	Torque strength	Main terminal M5	2.5 ~ 3.5	N·m
—	Torque strength	Mounting holes M6	3.5 ~ 4.5	N·m
—	Weight	Typical value	310	g

ELECTRICAL CHARACTERISTICS ($T_j = 25\text{ }^\circ\text{C}$)

Symbol	Item	Conditions	Min.	Typ.	Max.	Units	
I_{CES}	Collector cutoff current	$V_{CE}=V_{CES}, V_{GE}=0V$	—	—	1	mA	
$V_{GE(th)}$	Gate-emitter threshold voltage	$I_C=10mA, V_{CE}=10V$	6	7	8	V	
I_{GES}	Gate leakage current	$V_{GE}=V_{GES}, V_{CE}=0V$	—	—	0.5	μA	
$V_{CE(sat)}$	Collector to emitter saturation voltage	$T_j = 25\text{ }^\circ\text{C}$	—	1.8	2.5	V	
		$T_j = 125\text{ }^\circ\text{C}$					
C_{ies}	Input capacitance	$V_{CE}=10V$	—	—	23	nF	
C_{oes}	Output capacitance	$V_{GE}=0V$	—	—	2		
C_{res}	Reverse transfer capacitance		—	—	0.45		
Q_G	Total gate charge	$V_{CC}=600V, I_C=100A, V_{GE}=15V$	—	675	—	nC	
$t_{d(on)}$	Turn-on delay time	$V_{CC}=600V, I_C=100A$	—	—	120	ns	A
t_r	Turn-on rise time	$V_{GE1}=V_{GE2}=15V$	—	—	80		
$t_{d(off)}$	Turn-off delay time	$R_G=3.1\ \Omega$, Inductive load	—	—	450		
t_f	Turn-off fall time	switching operation	—	—	350		
t_{rr} ①	Reverse recovery time	$I_E=100A$	—	—	150	ns	A
Q_{rr} ①	Reverse recovery charge		—	5.0	—	μC	A
V_{EC} ①	Emitter-collector voltage	$I_E=100A, V_{GE}=0V$	—	—	3.2	V	
$R_{th(j-c)Q}$	Thermal resistance	IGBT part (1/2 module) *1	—	—	0.19	$^\circ\text{C/W}$	A
$R_{th(j-c)R}$		FWDi part(1/2 module) *1	—	—	0.35		
$R_{th(c-f)}$	Contact thermal resistance	Case to fin, Thermal compound Applied (1/2module) *2	—	0.07	—		
$R_{th(j-c)Q}$	Thermal resistance	IGBT part (1/2 module) *3	—	—	0.13		B
R_G	External gate resistance		3.1	—	31	Ω	

*1: T_c measured point is shown in page OUTLINE DRAWING.

*2: Typical value is measured by using Shin-etsu Silicone "G-746".

*3: T_c' measured point is just under the chips.

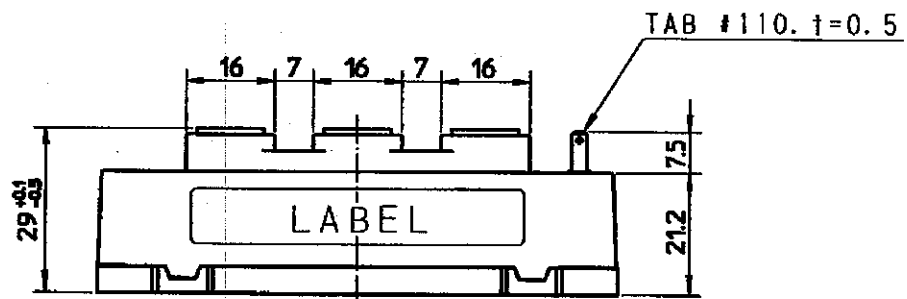
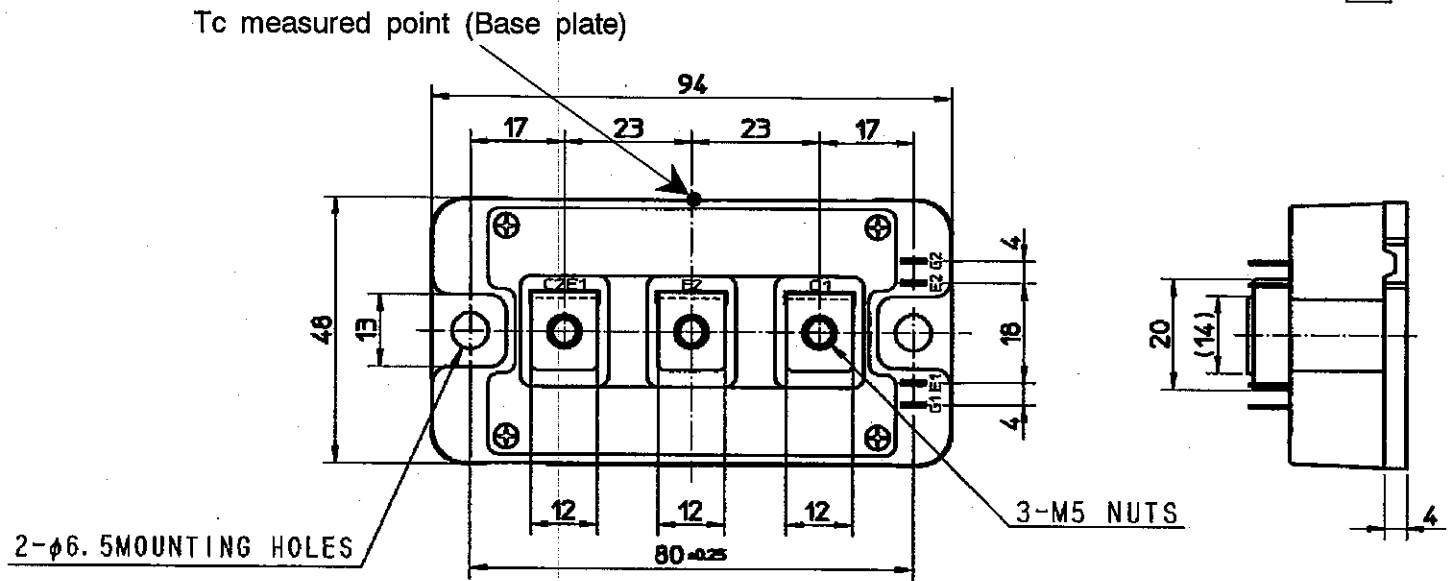
If you use this value, $R_{th}(f-a)$ should be measured just under the chips.

- ① $I_E, V_{EC}, t_{rr}, Q_{rr}$ & die/dt represent characteristics of the anti-parallel, emitter to collector free-wheel diode (FWDi).
- ② Pulse width and repetition rate should be such that the device junction temp. (T_j) dose not exceed T_{jmax} rating.
- ③ Junction temperature (T_j) should not increase beyond 150°C .
- ④ Pulse width and repetition rate should be such as to cause neglible temperature rise.

OUTLINE DRAWING

Dimensions in mm

A



CIRCUIT DIAGRAM

